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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/718,445	11/19/2003	Sandeep Bhatia	CA7035962001	9844

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EXAMINER	
TABONE JR, JOHN J	
ART UNIT	PAPER NUMBER
2117	

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Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Office Action Summary	Application No.	Applicant(s)	
	10/718,445	BHATIA, SANDEEP	
	Examiner	Art Unit	
	JOHN J. TABONE JR	2117	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE *3* MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

1)☒ Responsive to communication(s) filed on *11 April 2008*.

2a)☒ This action is **FINAL**. 2b)☐ This action is non-final.

3)☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

4)☒ Claim(s) *1-20* is/are pending in the application.

4a) Of the above claim(s) _____ is/are withdrawn from consideration.

5)☐ Claim(s) _____ is/are allowed.

6)☒ Claim(s) *1-20* is/are rejected.

7)☐ Claim(s) _____ is/are objected to.

8)☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

9)☐ The specification is objected to by the Examiner.

10)☒ The drawing(s) filed on *19 November 2003* is/are: a)☐ accepted or b)☐ objected to by the Examiner.

Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).

Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).

11)☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

12)☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).

a)☐ All b)☐ Some * c)☐ None of:

1.☐ Certified copies of the priority documents have been received.

2.☐ Certified copies of the priority documents have been received in Application No. _____.

3.☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

1) ☐ Notice of References Cited (PTO-892)
2) ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
3) ☐ Information Disclosure Statement(s) (PTO/SB/08) Paper No(s)/Mail Date _____.
4) ☐ Interview Summary (PTO-413) Paper No(s)/Mail Date. _____ .
5) ☐ Notice of Informal Patent Application
6) ☐ Other: _____.

DETAILED ACTION

1. Claims 1-20 were pending in the current application and have been examined. Claims 1, 5, 8, 11, 15 and 18 have been amended.

2. The 35 USC § 112, second paragraph rejections has been withdrawn by the Examiner as a result of Applicant's amendments filed 04/11/2008.

Response to Arguments

3. Applicant's arguments with respect to claims 1 and 11 have been considered but are moot in view of the new ground(s) of rejection.

Claim Rejections - 35 USC § 101

35 U.S.C. 101 reads as follows:

> Whoever invents or discovers any new and useful process, machine, manufacture, or composition of matter, or any new and useful improvement thereof, may obtain a patent therefor, subject to the conditions and requirements of this title.

4. Claims 1-20 are rejected under 35 U.S.C. 101 because the disclosed invention is inoperative and therefore lacks utility.

Claims 1 and 11:

These claims recite that the first and second scan chains comprises at least one positive triggered element and at least one negative triggered element and they are clocked from the same clock. This causes the invention to be inoperative because it is well known in the art that when a scan chain includes both positive and negative triggered flip-flops one should order them such that the negative triggered flip-flops are

at the beginning of the scan chain before the positive triggered flip-flops. Otherwise a single clock cycle will clock scan data through both flip-flops causing a potential race condition and lost of fault coverage. These claims do not recite a specific order of these elements. Further, if the flip-flops are not ordered as previously discussed (i.e. a negative triggered flip-flop follows a positive triggered flip-flop), a lockup latch must be inserted between the negative and positive triggered elements. This also, is not claimed. As such, the invention recited in claims 1 and 11 will not work as claimed and, therefore, is inoperative.

Claims 2-10 and 12-20:

These claims are also rejected because they depend on claims 1 and 11 respectively, and have the same problems of inoperativeness.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

> (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

5. Claims 1-9 and 11-19 are rejected under 35 U.S.C. 103(a) as being unpatentable over **Masatake** (JP-2003-202362), hereinafter Masatake, in view of **Jaramillo et al.**, (10 Tips for Successful Scan Design: Part two, February 17, 2000, ednmag.com, pp. 77-90), hereinafter Jaramillo.

Claims 1 and 11:

Masatake teaches scanning a first test data from an input pin (IN1, Drawing 1) into a first scan chain (Shift Register 11, Drawing 1) during a first state of a clock cycle (T3, Drawing 3) to test the integrated circuit and scanning a second test data from the input pin (IN1, Drawing 1) into a second scan chain (Shift Register 12, Drawing 1) during a second state of the clock cycle (T4, Drawing 3) to test the integrated circuit. **Masatake** also teaches "a clock signal (CLK) of the clock cycle is input to the first scan chain and the second scan chain during testing" in claim 1 and 2 where **Masatake** discloses "Said 1st shift register which operates synchronizing with the 1st edge of **said scanning clock**, said 2nd shift register which operates synchronizing with the 2nd edge of **said scanning clock**" (claim 1) where "said 1st edge being the rising edge and said 2nd edge being a falling edge" (claim 2). (Abstract, ¶s 37, 38, 47, 49, Drawings 1 and 3).

Masatake does not explicitly teach the first and second scan chains comprise at least one positive triggered element and at least one negative triggered element. However, **Masatake** does teach the first and second scan chains comprise at least one positive triggered element. **Jaramillo** teaches in an analogous art scan chains of BLOCKA and BLOCKB which comprise "at least one positive triggered element and at least one negative triggered element". (Fig. 3, page 82, first column, Mixing Flip-Flops). It would have been obvious to one of ordinary skill in the art at the time the invention was made to modify **Masatake's** Shift Registers 11 and 12 to include "at least one positive triggered element and at least one negative triggered element" as in **Jaramillo**. The artisan would be motivated to do so because it would enable **Masatake** to handle both positive and negative triggered elements, saving the time it takes to convert the

negative triggered elements to positive triggered elements in designing an integrated circuit.

Claims 2 and 12:

Masatake teaches receiving test data from the first scan chain at an output pin (OUT1, Drawing 1) during the first state of the clock cycle (T3, Drawing 3). (Abstract, ¶s 37, 38, 47, 49, Drawings 1 and 3).

Claims 3 and 13:

Masatake teaches receiving test data from the second scan chain at the output pin (OUT2, Drawing 1) during the second state of the clock cycle (T4, Drawing 3). (Abstract, ¶s 37, 38, 47, 49, Drawings 1 and 3).

Claims 4 and 14:

Masatake teaches sending test data from the first and second scan chains (Shift Register 11 and 12, Drawing 1) to a multiplexor (multiplexer 41, Drawing 1), applying a select signal to the multiplexor based on the state of the clock signal (CLK), and causing the multiplexor to output test data from either the first or second scan chain to the output pin based on the select signal (SCO1, Drawings 1 and 3). (Abstract, ¶s 37, 38, 47, 49, Drawings 1 and 3).

Claims 5 and 15:

Masatake view of **Jaramillo** teaches scanning the first test data by using a return-to-one clock waveform (T3, T4, T5, Drawing 3) and **using a mixture of positive and negative edge triggered scan flip-flops** in the first scan chain (Drawing 2). Masatake also teaches scanning the second test data by using the return-to-one clock

waveform (T3, T4, T5, Drawing 3) and **using a mixture of positive and negative edge triggered scan flip-flops** in the second scan chain (Drawing 2). (Abstract, ¶s 37, 38, 47, 49, Drawings 1-3).

Claims 6 and 16:

Masatake does not explicitly teach "**associating a lockup register with a beginning flip-flop or an ending flip-flop of the first or second scan chains based on return-to-one selection criteria**". Jaramillo teaches in an analogous art the general use of using a lockup register with a beginning flip-flop or an ending flip-flop of two separate scan chains. (Fig. 3, page 82). It would have been obvious to one of ordinary skill in the art at the time the invention was made to modify Masatake's design of Drawing 1 to include Jaramillo's design suggestions of using lockup latches when interfacing positive and negative edge clock scan flip-flops. The artisan would be motivated to do so because it would prevent Masatake's design of Drawing 1 from shifting data through both edged flip-flops in on clock cycle.

Claims 8 and 18:

These claims are an obvious alternate representation of claims 5 and 15 and, as such, are rejected as per these rejections. To use a return-to-zero selection criteria instead of return-to-one selection criteria is considered an alternate design choice.

Claims 9 and 19:

These claims are an obvious alternate representation of claims 6 and 16 and, as such, are rejected as per these rejections. To use a return-to-zero selection criteria instead of return-to-one selection criteria is considered an alternate design choice.

6. Claims 7, 10, 17 and 20 are rejected under 35 U.S.C. 103(a) as being unpatentable over Masatake (JP-2003-202362), hereinafter Masatake, in view of Jaramillo et al., (10 Tips for Successful Scan Design: Part two, February 17, 2000, ednmag.com, pp. 77-90), hereinafter Jaramillo, in further view of Morton (US 20040078741), hereinafter Morton.

Claims 7 and 17:

Masatake in view of Jaramillo does not explicitly teach "associating a negative edge triggered scan-in lockup register with the beginning flip-flop of the first scan chain if the beginning flip-flop of the first scan chain has a positive edge trigger", "associating a positive edge triggered scan-in lockup register with the beginning flip-flop of the second scan chain if the beginning flip-flop of the second scan chain has a negative edge trigger" and "associating a negative edge triggered scan-out lockup register if the ending flip-flop of the second scan chain has a negative edge trigger". However, Masatake in view of Jaramillo does teaches the general use of using a lockup register with a beginning flip-flop or an ending flip-flop of two separate scan chains to prevent a shoot-through condition. (Fig. 3, page 82). Morton teaches in an analogous art "associating a negative edge triggered scan-in lockup register with the beginning flip-flop of the first scan chain if the beginning flip-flop of the first scan chain has a positive edge trigger". (Fig. 2, ¶ 21). It would have been obvious to one of ordinary skill in the art at the time the invention was made to modify lockup latch configuration of Masatake in view of Jaramillo with Morton's design of Fig. 2. The artisan would be motivated to do so

because it would enable the lockup latch configuration of Masatake in view of Jaramillo to present input data IN1 of Drawing 1 to the input of scan chain 11 on the inactive portion of the clock, thus preventing shoot-through. Also, the claim limitations "associating a positive edge triggered scan-in lockup register with the beginning flip-flop of the second scan chain if the beginning flip-flop of the second scan chain has a negative edge trigger" and "associating a negative edge triggered scan-out lockup register if the ending flip-flop of the second scan chain has a negative edge trigger" are obvious design choices given the above mentioned modification to Masatake in view of Jaramillo.

Claims 10 and 20:

These claims are an obvious alternate representation of claims 7 and 17 and, as such, are rejected as per these rejections. To use a *positive edge* triggered scan-in lockup register with a *negative edge* trigger beginning flip-flop of the first scan chain instead of a *negative edge* triggered scan-in lockup register with a *positive edge* trigger beginning flip-flop of the first scan chain is considered an alternate design choice.

Conclusion

Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to JOHN J. TABONE JR whose telephone number is (571)272-3827. The examiner can normally be reached on M-F.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, JACQUES H. LOUIS JACQUES can be reached on (571) 272-6962. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/Cynthia Britt/
Primary Examiner, Art Unit 2117

/John J. Tabone, Jr./
Examiner
Art Unit 2117 07/09/2008

Search Notes (continued)

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/718,445	BHATIA, SANDEEP	
Examiner	**Art Unit**	
JOHN J. TABONE JR	2117	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
714/724,726,727,729,731 (text search only - see search history printout). UPDATED.	7/10/2008	JJT